



MOTOROLA

Octal D-Type Positive Edge-Triggered Flip-Flop With 3-State Outputs

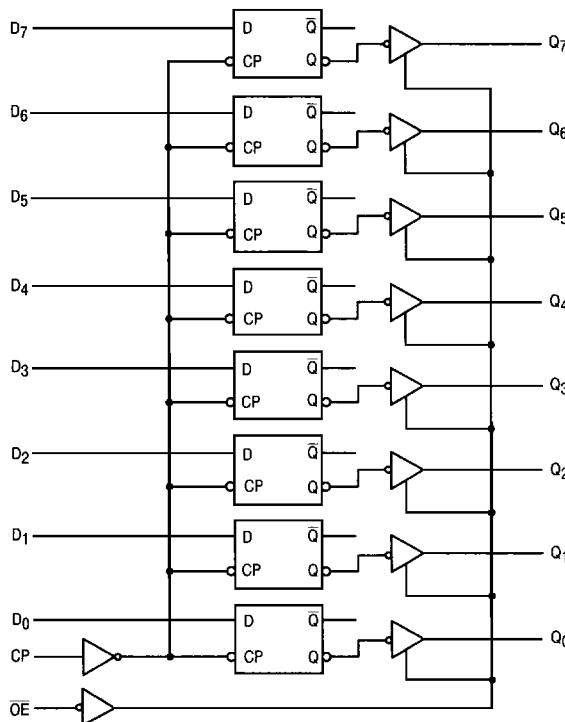
ELECTRICALLY TESTED PER:

MIL-M-38510/34105

The 54F374 is a high-speed, low-power octal D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-state outputs for bus oriented applications. A buffered Clock (CP) and Output Enable (\overline{OE}) are common to all flip-flops.

- Edge-Triggered D-Type Inputs
- Buffered Positive Edge-Triggered Clock
- 3-State Outputs for Bus Oriented Applications

LOGIC DIAGRAM



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Military 54F374



AVAILABLE AS:

- 1) JAN: JM38510/34105BXA
- 2) SMD: N/A
- 3) 883: 54F374/BXAJC

X = CASE OUTLINE AS FOLLOWS:

PACKAGE: CERDIP: R
CERFLAT: S
LCC: 2

THE LETTER "M" APPEARS
BEFORE THE / ON LCC.

PIN ASSIGNMENTS

FUNCT.	DIL 732-03	FLATS 737-02	LCC 756A-02	BURN-IN (COND. A)
\overline{OE}	1	1	1	VCC
Q_0	2	2	2	OPEN
D_0	3	3	3	VCC
D_1	4	4	4	VCC
Q_1	5	5	5	OPEN
Q_2	6	6	6	OPEN
D_2	7	7	7	VCC
D_3	8	8	8	VCC
Q_3	9	9	9	OPEN
GND	10	10	10	GND
CP	11	11	11	VCC
Q_4	12	12	12	OPEN
D_4	13	13	13	VCC
D_5	14	14	14	VCC
Q_5	15	15	15	OPEN
Q_6	16	16	16	OPEN
D_6	17	17	17	VCC
D_7	18	18	18	VCC
Q_7	19	19	19	OPEN
VCC	20	20	20	VCC

BURN-IN CONDITIONS:

$V_{CC} = 5.0 \text{ V MIN}/6.0 \text{ V MAX}$

FUNCTIONAL DESCRIPTION

The 'F374 contains eight edge-triggered flip-flops with individual D-type inputs and 3-state true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold times requirements on the

LOW-to-HIGH Clock (CP) transition. With the Output Enable (OE) LOW, the contents of the eight flip-flops are available at the outputs. When \overline{OE} is HIGH, the outputs go to the high impedance state. Operation of the \overline{OE} input does not affect the state of the flip-flops.

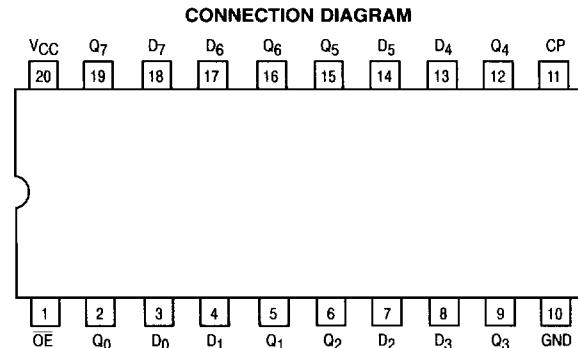
TRUTH TABLE			
Inputs		Outputs	
D _n	CP	OE	Q _n
H	—	L	H
L	—	L	L
X	X	H	Z

H = HIGH Voltage Level

L = LOW Voltage Level

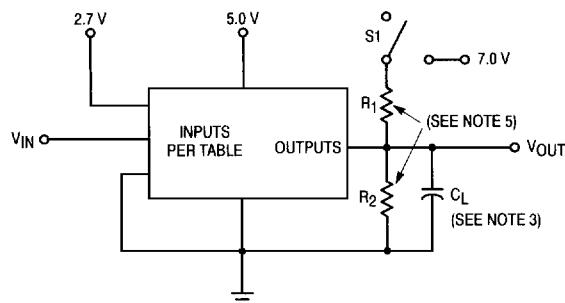
X = Immaterial

Z = HIGH Impedance

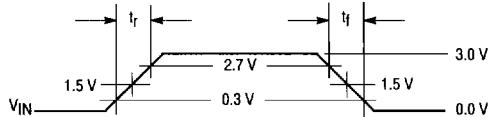


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AC TEST CIRCUIT

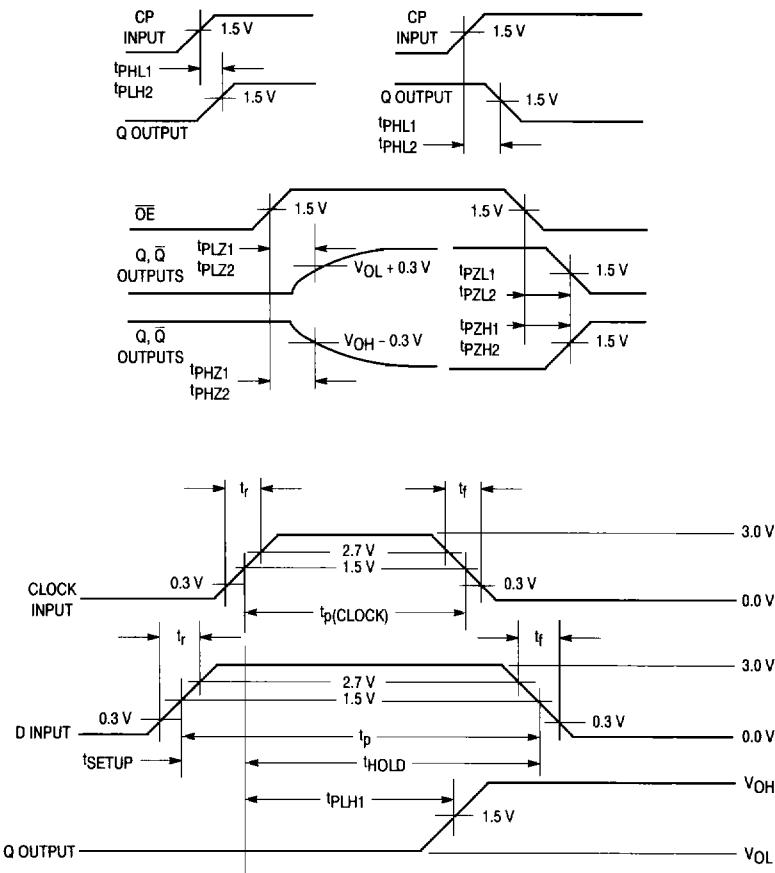


Test Type	S1
t _{PLH}	open
t _{PHL}	open
t _{PHZ}	open
t _{PZH}	open
t _{PLZ}	closed
t _{PZL}	closed



REFERENCE NOTES ON PAGE 4-170

WAVEFORMS



Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)		
	Static Parameters:	+ 25°C		+ 125°C		- 55°C					
		Subgroup 1		Subgroup 2		Subgroup 3					
		Min	Max	Min	Max	Min	Max				
V _{OH}	Logical "1" Output Voltage	2.5		2.5		2.5		V	V _{CC} = 4.5 V, I _{OH} = -1.0 mA, OE = 0.8 V, CP = (See Note 6), V _{IH} = 2.0 V.		
V _{OL}	Logical "0" Output Voltage		0.5		0.5		0.5	V	V _{CC} = 4.5 V, I _{OL} = 20 mA, V _{IL} = 0.8 V, (all inputs), CP = (See Note 6).		
V _{IC}	Input Clamping Voltage		-1.2					V	V _{CC} = 4.5 V, I _{IN} = -18 mA, other inputs are open.		
I _{IH}	Logical "1" Input Current		20		20		20	μA	V _{CC} = 5.5 V, V _{IH} = 2.7 V, other inputs are open.		
I _{IHH}	Logical "1" Input Current		100		100		100	μA	V _{CC} = 5.5 V, V _{IHH} = 7.0 V, other inputs are open.		
I _{OD}	Diode Current	35		35		35		mA	V _{CC} = 4.5 V, V _{IN} = 5.5 V (all inputs), CP = (See Note 6), V _{OUT} = 2.5 V.		
I _{IL}	Logical "0" Input Current	-0.03	-0.6	-0.03	-0.6	-0.03	-0.6	mA	V _{CC} = 5.5 V, V _{IN} = 0.5 V, other inputs are open.		
I _{OS}	Output Short Circuit Current	-60	-150	-60	-150	-60	-150	mA	V _{CC} = 5.5 V, V _{IN} = 4.5 V (other inputs open) V _{OUT} = 0.0 V, CP = (See Note 6).		
I _{IOZH}	Output Off Current High		50		50		50	μA	V _{CC} = 5.5 V, V _{IN} = 0 V (other inputs open), V _{OUT} = 2.7 V, OE = 2.0 V.		
I _{IOZL}	Output Off Current Low		-50		-50		-50	μA	V _{CC} = 5.5 V, V _{IN} = 4.5 V (other inputs open), V _{OUT} = 0.5 V, OE = 2.0 V.		
I _{CCZ}	Power Supply Current Off		86		86		86	mA	V _{CC} = 5.5 V, V _{IN} = 4.5 V (all inputs).		
V _{IH}	Logical "1" Input Voltage	2.0		2.0		2.0		V	V _{CC} = 4.5 V.		
V _{IL}	Logical "0" Input Voltage		0.8		0.8		0.8	V	V _{CC} = 4.5 V.		
	Functional Tests	Subgroup 7		Subgroup 8A		Subgroup 8B			per Truth Table with V _{CC} = 4.5 V, (Repeat at) V _{CC} = 5.5 V, V _{INL} = 0.5 V, and V _{INH} = 2.5 V.		

Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)		
		+ 25°C		+ 125°C		- 55°C					
		Subgroup 9		Subgroup 10		Subgroup 11					
		Min	Max	Min	Max	Min	Max				
t_{PHL1}	Propagation Delay /Data-Output CP to Q_n	3.0	8.5	3.0	11	3.0	11	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega$		
t_{PLH1}	Propagation Delay /Data-Output CP to Q_n	3.0	8.5	3.0	10.5	3.0	10.5	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega$		
t_{PLZ1}	Propagation Delay /Data-Output Output Low-High	1.5	6.5	1.5	7.5	1.5	7.5	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega$		
t_{PHZ1}	Propagation Delay /Data-Output Output High-Low	1.5	7.5	1.5	8.0	1.5	8.0	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega$		
t_{PZL1}	Propagation Delay /Data-Output Output Low-High	2.0	7.5	2.0	10	2.0	10	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega$		
t_{PZH1}	Propagation Delay /Data-Output Output High-Low	2.0	11.5	2.0	14	2.0	14	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega$		
f_{MAX}	Maximum Clock Frequency	80		60		60		MHz	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 8})$		
$t_{S(H)}$	Setup Time, HIGH D_n to CP	2.5		2.5		2.5		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7})$		
$t_{S(L)}$	Setup Time, LOW D_n to CP	2.0		2.0		2.0		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7})$		
$t_{H(H)}$	Hold Time, HIGH D_n to CP	2.0		2.0		2.0		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7})$		
$t_{H(L)}$	Hold Time, LOW D_n to CP	2.5		2.5		2.5		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7})$		

NOTES:

1. V_{IN} = Input pulse has the following characteristics: $t_r = t_f \leq 2.5 \text{ ns}$, $\text{PRR} \leq 1.0 \text{ MHz}$.
2. Terminal conditions (pins not designated may be high $\geq 2.0 \text{ V}$, low $\leq 0.8 \text{ V}$, or open).
3. $C_L = 50 \text{ pF} \pm 10\%$ including scope probe, wiring and stray capacitance, without package in test fixture.
4. Voltage measurements are to be made with respect to network ground terminal.
5. $R_1 = R_2 = 499 \Omega \pm 5.0\%$.
6. Apply all voltages, then apply 3.0 V, 0V, 3.0 V to CP, then make measurement.
7. This is for information only, no test required.
8. f_{MAX} : minimum limit specified is the frequency of the input pulse. The output frequency shall be 1/2 the input frequency.